

FORM PTO-1449 (modified)
To: U.S. Department of Commerce
(PW FORM PAT-1449)
Patent and Trademark Office

Atty.
Dkt. No.

M#

Client Ref.

284101

OSP-11726

Applicant: HASEGAWA et al.

Appln. No.: DIV. of 09/651,255

Filing Date: Herewith

Examiner: Pert, F.

Group Art Unit: 2813

**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**

Date: December 19, 2001

Page

1

of

1

U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
	AR					
	BR					
	CR					
	DR					
	ER					
	FR					
	GR					
	HR					
	IR					
	JR					
	KR					
	LR					
	MR					
	NR					

FOREIGN PATENT DOCUMENTS

		Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract		Translation Readily Available	
						Enclosed	No	Enclose	No
UK	OR	5-99845	04/1993	Japan	TAKEUCHI et al.	X			X
1	PR	11-57390	03/1999	Japan	SHIRAI et al.	X			X
1	QR	99/30809	06/1999	WIPO	OHMI	X			X
1	RR	11-183366	07/1999	Japan	SATO et al.	X			X
UK	SR	968 753	01/2000	Europe	OHMI et al.				
	TR								
	UR								
	VR								

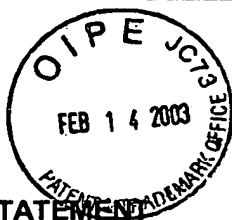
OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

UK	WR	Masusaki et al., Nippon Sanso Giho (Nippon Sanso Technical Reports), "Monitoring of Impurities in Si Epitaxial Gases by Use of Near-Infrared Laser Diode Spectroscopy," December 3, 1999, No. 18, pp. 32-33							
UK	XR	Microsystem Technology Laboratories Annual Report, Massachusetts Institute of Technology, May 1999							
	YR								
	ZR								
	AAR								
	BBR								

Examiner

Date Considered: 7/6/99

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.



Atty.
Dkt. No.

M#

Client Ref.

284101

OSP-11726

**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**

Applicant: HASEGAWA et al.

Appln. No.: 10/021,259

Filing Date: December 19, 2001

Date: February 14, 2003

Page

1

of

1

Examiner: Unknown

Group Art Unit: Unknown

U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
IAK	AR 6,197,699 B1	03/2001	Fritzinger et al.	438	710	
IAK	BR 4,847,512	07/1989	Seta	250	575	
	CR					
	DR					
	ER					
	FR					
	GR					
	HR					
	IR					
	JR					
	KR					
	LR					
	MR					
	NR					

FOREIGN PATENT DOCUMENTS

ORIGINAL PATENT DOCUMENTS						Abstract		Readily Available		
		Document Number	Date MM/YYYY	Country	Inventor Name		Enclosed	No	Enclose	No
IAK	OR	JP10125609A	05/1998	Japan	Koji		X			
IAK	PR	WO99/34192A	07/1999	WIPO	Satoh et al.		X			
IAK	QR	JP6186149	07/1994	Japan	Hasegawa et al.		X			
	RR									
	SR									
	TR									
	UR									
	VR									
	WR									
	XR									

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

	YR	
	ZR	
	AAR	
	BBR	
	CCR	
	DDR	

Examiner

Date Considered: 7/6/97

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re PATENT APPLICATION of

Inventor(s): HASEGAWA et al.

Atty. Dkt: 61063/284101

Appln. No.: 10/021,259

Fil d: December 19, 2001

FOR: METHOD OF PURGING CVD APPARATUS AND METHOD FOR JUDGING
MAINTENANCE OF TIMES OF SEMICONDUCTOR PRODUCTION APPARATUSES

Group Art Unit: Unknown

Examiner: Unknown

Unknown

Unknown

2651
#3
#6/IDS
3/20/03
Hayes



Date: February 25, 2002

IDS LETTER CITING APPLICATION(S)

RECEIVED

FEB 27 2002

GROUP 3600

The Examiner's attention is directed to the following application(s) of:

Examiner's Initials*	FIRST INVENTOR (Last Name Only)	APPLICATION NO. & Filing Date	ENCLOSED
LAK	OMI	09/096,986 June 12, 1998	<input checked="" type="checkbox"/> Spec <input checked="" type="checkbox"/> Drawings <input checked="" type="checkbox"/> Original Claims <input checked="" type="checkbox"/> Other Abstract
		now 6,431,353	<input type="checkbox"/> Spec <input type="checkbox"/> Drawings <input type="checkbox"/> Current Claims <input type="checkbox"/> Other
			<input type="checkbox"/> Spec <input type="checkbox"/> Drawings <input type="checkbox"/> Current Claims <input type="checkbox"/> Other

PLEASE DO NOT PRINT the above information on the patent which results from the subject application.

This IDS is being filed within 3 months of the filing date of this application, and hence this IDS must be considered per Rule 97(b)(1).

Consideration of each listed application is earnestly solicited since unpublished patent applications are contemplated as IDS material; see the exception in Rule 98(a)(2)(iii) and note the penultimate sentence of MPEP 609.

Further, in keeping with MPEP 609, Subsec. C(2), 2nd para., line 10 to end of the paragraph (especially note lines 18-25) **PLEASE RETURN A COPY OF THIS LETTER** with the Examiner's initials adjacent each above listing so that applicant will know that each listed application has been considered as required by PTO policy. Thanks.

Respectfully submitted

[Signature]

G. Lloyd Knight
Reg. No 17698
Tel. No. (703) 905-2117
Fax No. (703) 905-2500

Pillsbury Winthrop LLP
1600 Tysons Boulevard
McLean, VA 22102

Li Als
7/6/4
Considered

RECEIVED
MAR 12 2003
TECHNOLOGY CENTER 2800

*The Examiner's initials adjacent a citation indicates he/she has considered the cited application relative to the subject application.

